Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/073,106	YAMAMOTO ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	831 832 840 841 844 846 851 854	6/30/2005	PK
156	64 356	,	
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228	175 227	6/30/2005	PK
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174	259 260	7/1/2005	PK
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PGPub Text Search see attachment		10/24/2006	PK

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
Text Search EAST/NPL (IEEE)	7/1/2005	PK
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Scott Geyer (438)	2/2/2006	PK
Updated Text Search EAST	2/2/2006	PK
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Updated Text Search EAST/PGPub	10/24/2006	PK